Abstracts

Characterization of Conductor-Backed Coplanar Waveguide Using Accurate On-Wafer Measurement Techniques

Y.-C. Shih and M. Maher. "Characterization of Conductor-Backed Coplanar Waveguide Using Accurate On-Wafer Measurement Techniques." 1990 MTT-S International Microwave Symposium Digest 90.3 (1990 Vol. III [MWSYM]): 1129-1132.

The conductor-backed coplanar waveguide has been experimentally characterized using accurate on-wafer S-parameter measurement techniques. An uncertainty analysis was conducted to quantify the measurement errors. Measured characteristic impedance, effective dielectric constant, and attenuation constant are in good agreement with the theory.

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